74LCX16374

LOW VOLTAGE CMOS 16-BIT D-TYPE FLIP-FLOP (3-STATE) WITH 5V TOLERANT INPUTS AND OUTPUTS

- 5V TOLERANT INPUTS AND OUTPUTS
- HIGH SPEED :
  f_{MAX} = 150MHz (MIN.) at V_{CC} = 3V
- POWER DOWN PROTECTION ON INPUTS AND OUTPUTS
- SYMMETRICAL OUTPUT IMPEDANCE:
  $|I_{OH}| = I_{OL}$ = 24mA (MIN) at V_{CC} = 3V
- PCI BUS LEVELS GUARANTEED AT 24 mA
- BALANCED PROPAGATION DELAYS:
  $t_{PLH} \cong t_{PHL}$
- OPERATING VOLTAGE RANGE:
  V_{CC}(OPR) = 2.0V to 3.6V (1.5V Data Retention)
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 16374
- LATCH-UP PERFORMANCE EXCEEDS 500mA (JESD 17)
- ESD PERFORMANCE:
  HBM > 2000V (MIL STD 883 method 3015);
  MM > 200V

DESCRIPTION

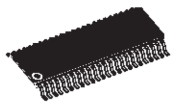
The 74LCX16374 is a low voltage CMOS 16 BIT D-TYPE FLIP-FLOP with 3 STATE OUTPUTS NON INVERTING fabricated with sub-micron silicon gate and double-layer metal wiring C^{2}MOS technology. It is ideal for low power and high speed 3.3V applications; it can be interfaced to 5V signal environment for both inputs and outputs.

These 16 bit D-TYPE flip-flops are controlled by two clock inputs (nCK) and two output enable inputs(n$\overline{OE}$). On the positive transition of the (nCK), the nQ outputs will be set to the logic state that were setup at the nD inputs. While the (n$\overline{OE}$) input is low, the 8 outputs (nQ) will be in a normal state (high or low logic level) and while high level the outputs will be in a high impedance state.

Any output control does not affect the internal operation of flip flops; that is, the old data can be retained or the new data can be entered even while the outputs are off.

It has same speed performance at 3.3V than 5V AC/ACT family, combined with a lower power consumption.

All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

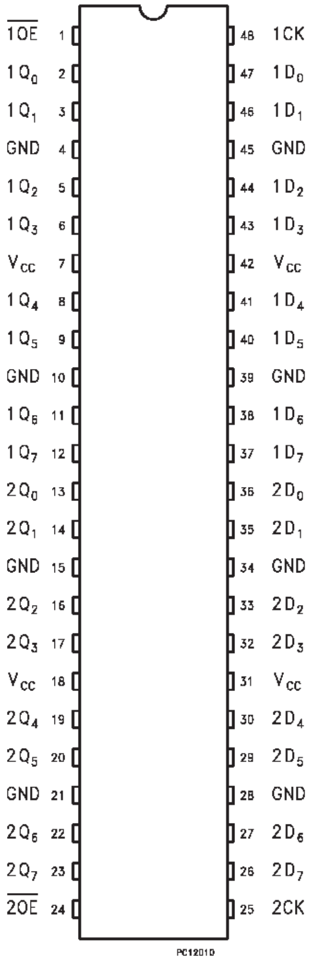


TSSOP

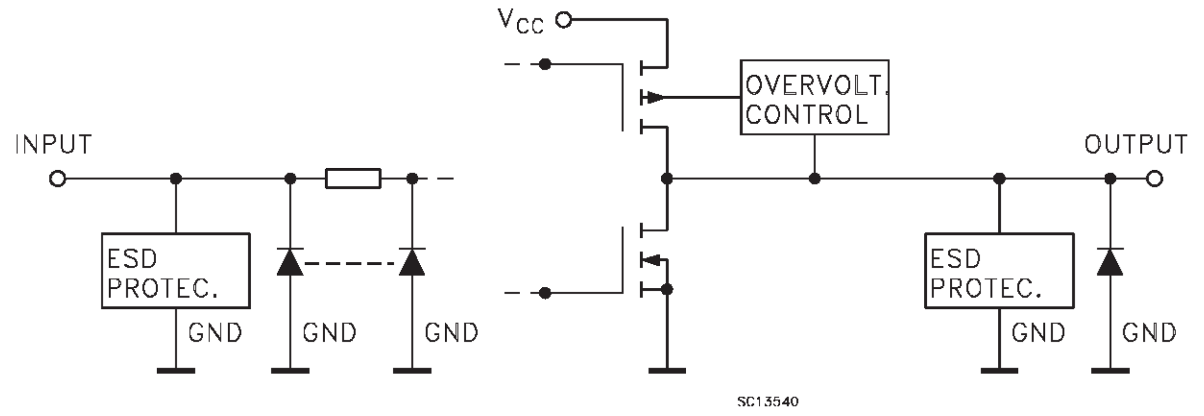
ORDER CODES

PACKAGE	TUBE	T & R
TSSOP		74LCX16374TTR

PIN CONNECTION



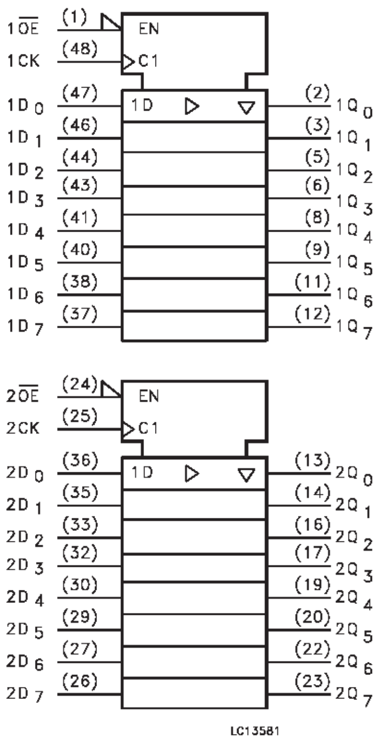
INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
1	$1\overline{OE}$	3 State Output Enable Input (Active LOW)
2, 3, 5, 6, 8, 9, 11, 12	1Q0 to 1Q7	3-State Outputs
13, 14, 16, 17, 19, 20, 22, 23	2Q0 to 2Q7	3-State Outputs
24	$2\overline{OE}$	3 State Output Enable Input (Active LOW)
25	2CK	Latch Enable Input
36, 35, 33, 32, 30, 29, 27, 26	2D0 to 2D7	Data Inputs
47, 46, 44, 43, 41, 40, 38, 37	1D0 to 1D7	Data Inputs
48	1CK	Latch Enable Input
4, 10, 15, 21, 28, 34, 39, 45	GND	Ground (0V)
7, 18, 31, 42	V_{CC}	Positive Supply Voltage

IEC LOGIC SYMBOLS

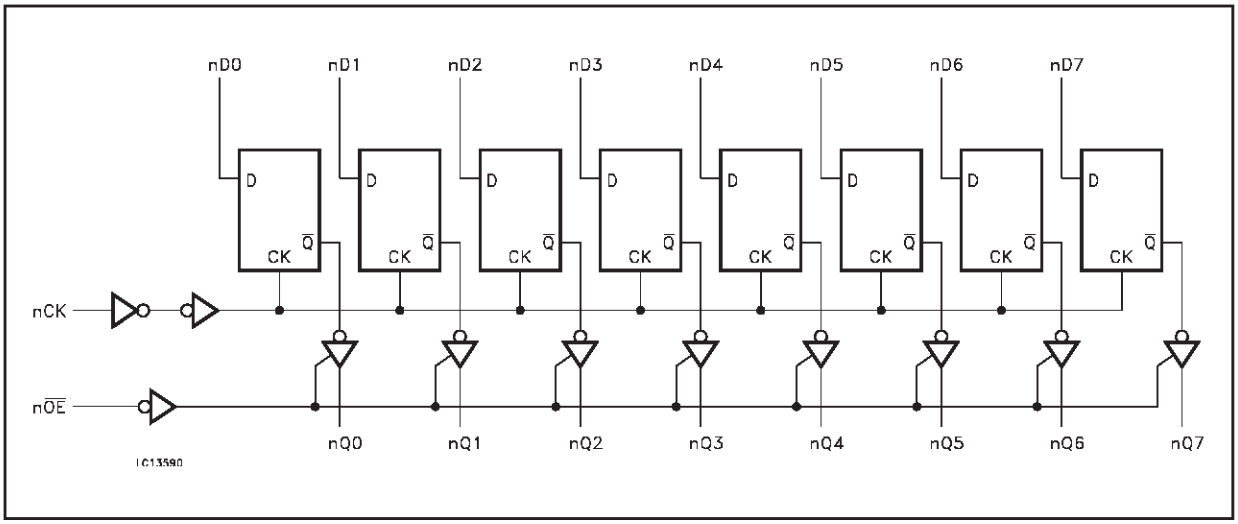


TRUTH TABLE

INPUTS			OUTPUT
$\overline{OE}$	CK	D	Q
H	X	X	Z
L	↓	X	NO CHANGE*
L	↑	L	L
L	↑	H	H

X : Don‘t Care
Z : High Impedance

LOGIC DIAGRAM



This logic diagram has not to be used to estimate propagation delays

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7.0	V
V_I	DC Input Voltage	-0.5 to +7.0	V
V_O	DC Output Voltage (OFF State)	-0.5 to +7.0	V
V_O	DC Output Voltage (High or Low State) (note 1)	-0.5 to V_{CC} + 0.5	V
I_{IK}	DC Input Diode Current	- 50	mA
I_{OK}	DC Output Diode Current (note 2)	- 50	mA
I_O	DC Output Current	± 50	mA
I_{CC}	DC Supply Current per Supply Pin	± 100	mA
I_{GND}	DC Ground Current per Supply Pin	± 100	mA
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied

1) I_O absolute maximum rating must be observed
2) V_O < GND

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage (note 1)	2.0 to 3.6	V
V_I	Input Voltage	0 to 5.5	V
V_O	Output Voltage (OFF State)	0 to 5.5	V
V_O	Output Voltage (High or Low State)	0 to V_{CC}	V
I_{OH}, I_{OL}	High or Low Level Output Current (V_{CC} = 3.0 to 3.6V)	± 24	mA
I_{OH}, I_{OL}	High or Low Level Output Current (V_{CC} = 2.7V)	± 12	mA
T_{op}	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time (note 2)	0 to 10	ns/V

1) Truth Table guaranteed: 1.5V to 3.6V
2) V_{IN} from 0.8V to 2V at V_{CC} = 3.0V

DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value				Unit
		V_{CC} (V)		-40 to 85 °C		-55 to 125 °C		
				Min.	Max.	Min.	Max.	
V_{IH}	High Level Input Voltage	2.7 to 3.6		2.0		2.0		V
V_{IL}	Low Level Input Voltage				0.8		0.8	V
V_{OH}	High Level Output Voltage	2.7 to 3.6	I_O=-100 µA	V_{CC}-0.2		V_{CC}-0.2		V
		2.7	I_O=-12 mA	2.2		2.2		
		3.0	I_O=-18 mA	2.4		2.4		
			I_O=-24 mA	2.2		2.2		
V_{OL}	Low Level Output Voltage	2.7 to 3.6	I_O=100 µA		0.2		0.2	V
		2.7	I_O=12 mA		0.4		0.4	
		3.0	I_O=16 mA		0.4		0.4	
			I_O=24 mA		0.55		0.55	
I_I	Input Leakage Current	2.7 to 3.6	V_I = 0 to 5.5V		± 5		± 5	µA
I_{off}	Power Off Leakage Current	0	V_I or V_O = 5.5V		10		10	µA
I_{OZ}	High Impedance Output Leakage Current	2.7 to 3.6	V_I = V_{IH} or V_{IL} V_O = 0 to V_{CC}		± 5		± 5	µA
I_{CC}	Quiescent Supply Current	2.7 to 3.6	V_I = V_{CC} or GND		20		20	µA
			V_I or V_O= 3.6 to 5.5V		± 20		± 20	
ΔI_{CC}	I_{CC} incr. per Input	2.7 to 3.6	V_{IH} = V_{CC} - 0.6V		500		500	µA

DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Condition		Value			Unit
		V_{CC} (V)		T_A = 25 °C			
				Min.	Typ.	Max.	
V_{OLP}	Dynamic Low Level Quiet Output (note 1)	3.3	C_L = 50pF V_{IL} = 0V, V_{IH} = 3.3V		0.8		V
V_{OLV}					-0.8		

1) Number of outputs defined as "n". Measured with "n-1" outputs switching from HIGH to LOW or LOW to HIGH. The remaining output is measured in the LOW state.

AC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Condition				Value				Unit
		V_{CC} (V)	C_L (pF)	R_L (Ω)	$t_s = t_r$ (ns)	-40 to 85 °C		-55 to 125 °C		
						Min.	Max.	Min.	Max.	
t_{PLH} t_{PHL}	Propagation Delay Time	2.7	50	500	2.5	1.5	6.5	1.5	6.5	ns
		3.0 to 3.6				1.5	6.2	1.5	6.2	
t_{PZL} t_{PZH}	Output Enable Time to HIGH and LOW level	2.7	50	500	2.5	1.5	6.3	1.5	6.3	ns
		3.0 to 3.6				1.5	6.1	1.5	6.1	
t_{PLZ} t_{PHZ}	Output Disable Time from HIGH and LOW level	2.7	50	500	2.5	1.5	6.2	1.5	6.2	ns
		3.0 to 3.6				1.5	6.0	1.5	6.0	
t_S	Set-Up Time, HIGH or LOW level (Dn to CK)	2.7	50	500	2.5	2.5		2.5		ns
		3.0 to 3.6				2.5		2.5		
t_h	Hold Time, HIGH or LOW level (Dn to CK)	2.7	50	500	2.5	1.5		1.5		ns
		3.0 to 3.6				1.5		1.5		
t_W	CK Pulse Width, HIGH or LOW	2.7	50	500	2.5	3.0		3.0		ns
		3.0 to 3.6				3.0		3.0		
f_{MAX}	Clock Pulse Frequency	3.0 to 3.6	50	500	2.5	170		150		MHz
t_{OSLH} t_{OSHL}	Output To Output Skew Time (note1, 2)	3.0 to 3.6	50	500	2.5		1.0		1.0	ns

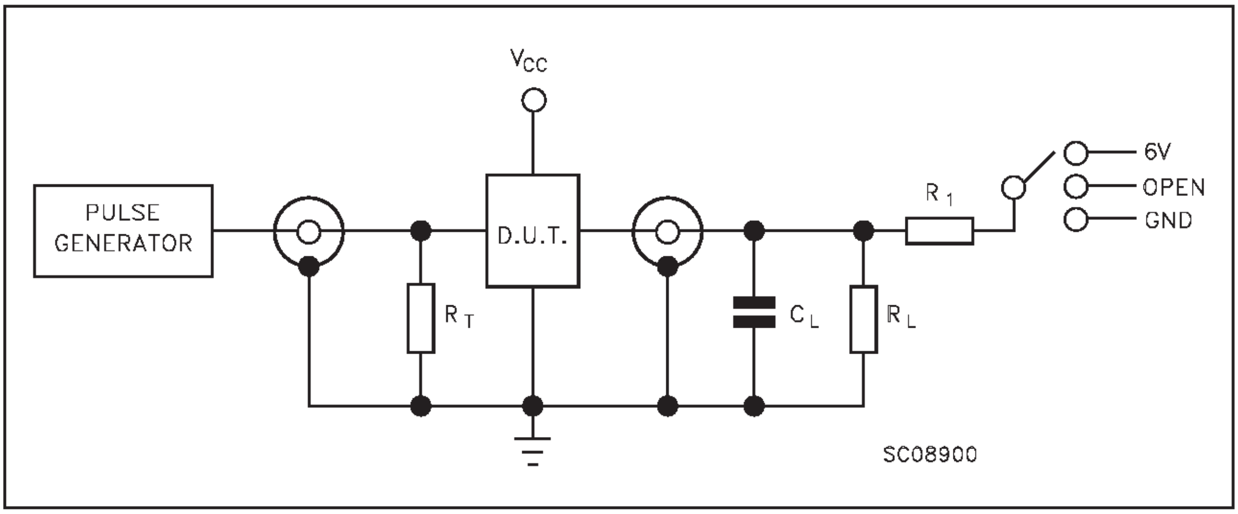
1) Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW ($t_{OSLH} = | t_{PLHm} - t_{PLHn}|$, $t_{OSHL} = | t_{PHLm} - t_{PHLn}|$)
2) Parameter guaranteed by design

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Condition		Value			Unit
		V_{CC} (V)		T_A = 25 °C			
				Min.	Typ.	Max.	
C_{IN}	Input Capacitance	3.3	V_{IN} = 0 to V_{CC}		7		pF
C_{OUT}	Output Capacitance	3.3	V_{IN} = 0 to V_{CC}		8		pF
C_{PD}	Power Dissipation Capacitance (note 1)	3.3	f_{IN} = 10MHz V_{IN} = 0 or V_{CC}		20		pF

1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/16$ (per circuit)

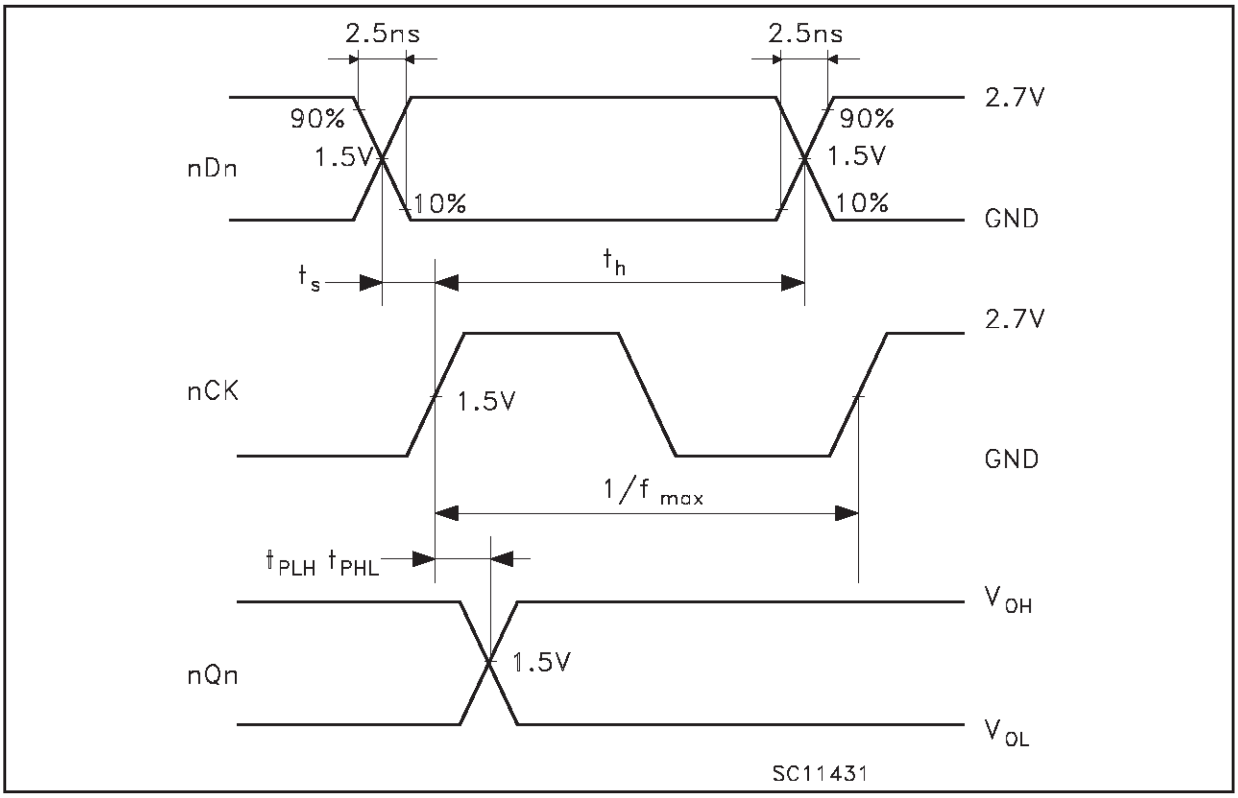
TEST CIRCUIT



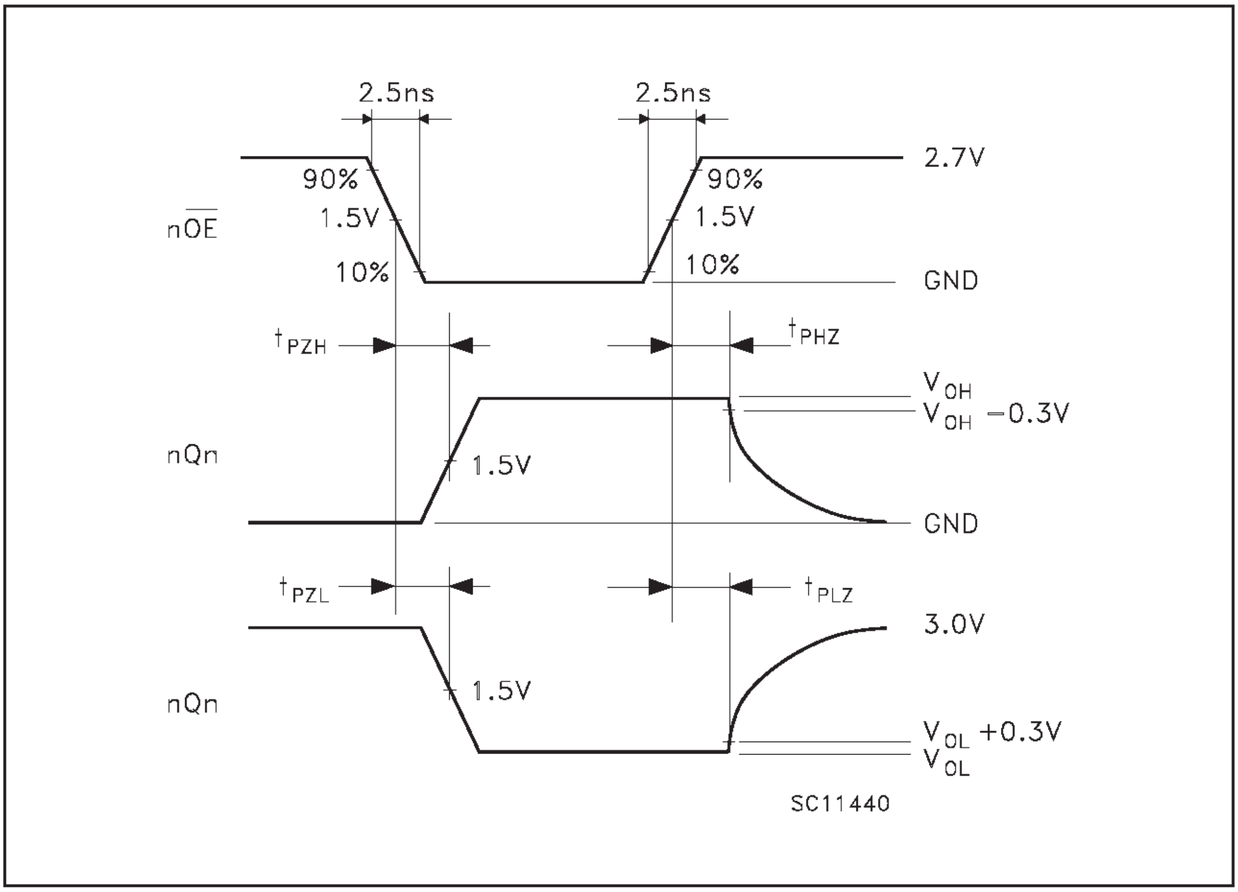
TEST	SWITCH
t_{PLH}, t_{PHL}	Open
t_{PZL}, t_{PLZ}	6V
t_{PZH}, t_{PHZ}	GND

C_L = 50 pF or equivalent (includes jig and probe capacitance)
R_L = R1 = 500Ω or equivalent
R_T = Z_{OUT} of pulse generator (typically 50Ω)

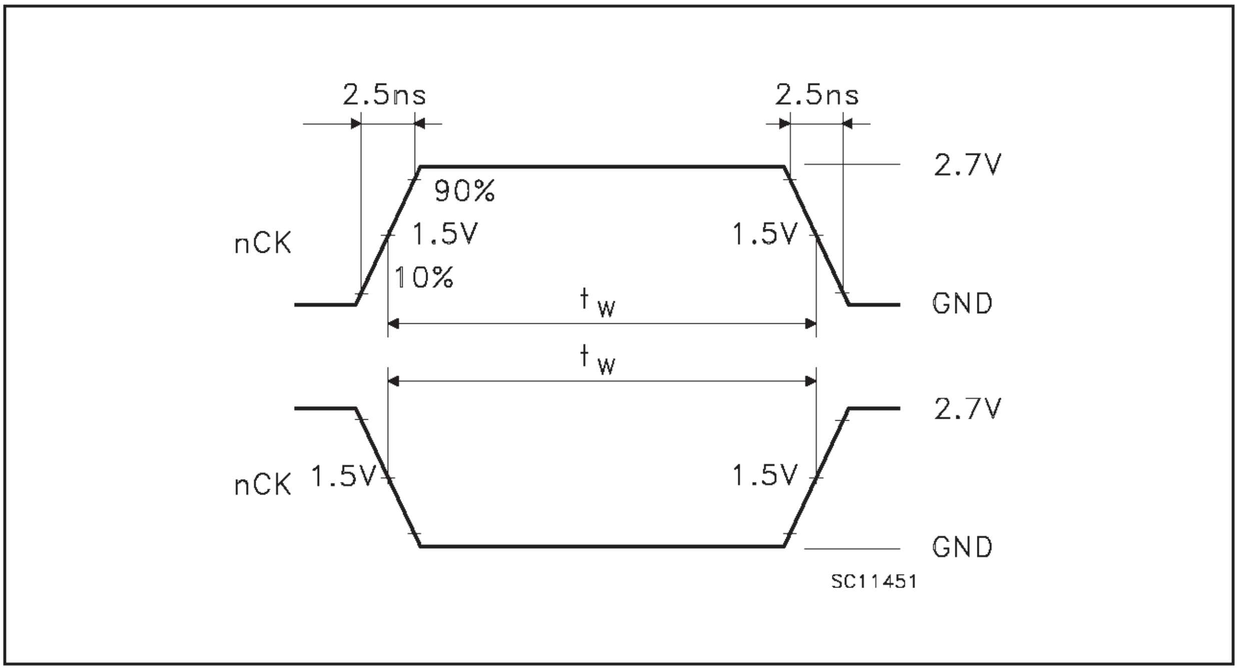
WAVEFORM 1 : PROPAGATION DELAYS, SETUP AND HOLD TIMES, MAXIMUM CLOCK FREQUENCY (f=1MHz; 50% duty cycle)



WAVEFORM 2: OUTPUT ENABLE AND DISABLE TIME (f=1MHz; 50% duty cycle)

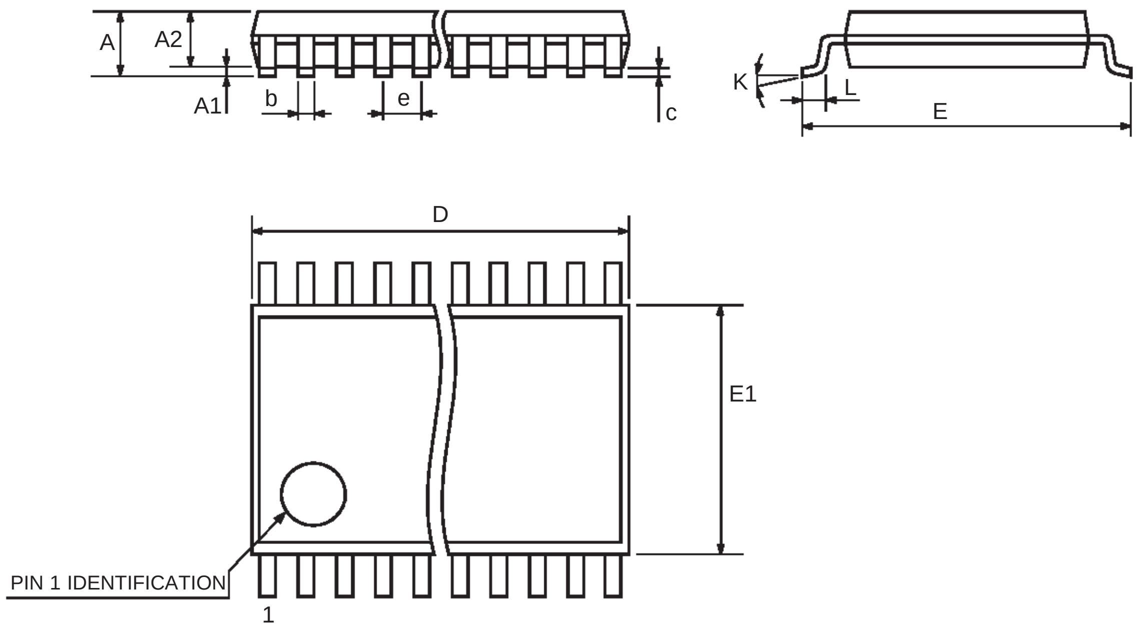


WAVEFORM 3 : PULSE WIDTH (f=1MHz; 50% duty cycle)



TSSOP48 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.1			0.043
A1	0.05		0.15	0.002		0.006
A2		0.9			0.035	
b	0.17		0.27	0.0067		0.011
c	0.09		0.20	0.0035		0.0079
D	12.4		12.6	0.408		0.496
E	7.95		8.25	0.313		0.325
E1	6.0		6.2	0.236		0.244
e		0.5 BSC			0.0197 BSC	
K	0°		8°	0°		8°
L	0.50		0.75	0.020		0.030



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